# RENESAS

# DATASHEET

### ISL58831

Dual Laser Driver with APC Amplifier and Spread Spectrum Oscillator

FN7440 Rev 1.00 Jan 28, 2016

The  $15L58831$  is a combination read + 3 write level laser driver and IV amplifier, with an extra read + oscillator ROM channel for use in dual-laser 'Combo' drivers. A separate (amplitude and frequency) oscillator modulates the selected output for laser noise reduction during read or write. All these functions are provided in a 24 Ld QFN package.

The SEL1 pin, when high, selects the DVD (write) laser. Positive current supplied to the  $I_{IN}$  lines, through a user-selected resistor, allow the full-scale range of each amplifier to be matched to the full-scale range of the users control DACs. When the write laser is selected, and the WEN pins are switched low, the respective current is summed to the output with 1ns rise and fall times. Write channel 2 has 240mA output capability with an 250X gain amplifier.

The 100mA<sub>P-P</sub> (maximum) oscillator is switched on and off by the OSCEN line. The SEL1 line allows the oscillator to operate at different amplitudes and frequencies for each laser.

The entire chip is powered down when ENABLE is low. The user can define the gain of the I/V amplifier. With a slew rate of  $200V/\mu s$ , the I/V amplifier can normally settle to 1% within 30ns.

An internal spread spectrum circuit modulates the oscillator frequency to help reduce peak EMI.

### Features

- "Shrink-small" outline package
- Voltage-controlled output current source requiring one external set resistor per channel
- Current-controlled output current source
- CH2 to 235mA maximum
- CH3 to 170mA maximum
- CH4 to 100mA maximum
- $\cdot$  Rise time = 0.8ns
- $\cdot$  Fall time = 0.8ns
- On-chip oscillator with frequency and amplitude control by use of external resistors to ground
- Oscillator to 600MHz
- Oscillator to 100mA<sub>P-P</sub>
- $\cdot$  Single +5V supply ( $\pm 10\%$ )
- Disable feature for power-up protection and power savings
- $\cdot$  200V/µs I/V amplifier
- Internal spread spectrum modulation to reduce peak EMI
- Pb-free (RoHS compliant)

### Applications

- ï Combo CD-R + DVD-R
- DVD±RW to 8X
- Writable optical disk drives



### Typical Application





### Ordering Information



NOTES:

<span id="page-1-0"></span>2. Intersil Pb-free plus anneal products employ special Pb-free material sets; molding compounds/die attach materials and 100% matte tin plate termination finish, which are RoHS compliant and compatible with both SnPb and Pb-free soldering operations. Intersil Pb-free products are MSL classified at Pb-free peak reflow temperatures that meet or exceed the Pb-free requirements of IPC/JEDEC J STD-020.

<span id="page-1-1"></span>3. For Moisture Sensitivity Level (MSL), please see product information page for **ISL58831**. For more information on MSL, please see tech brief [TB363](http://www.intersil.com/content/dam/Intersil/documents/tb36/tb363.pdf).



<span id="page-1-2"></span><sup>1.</sup> Please refer to **[TB347](http://www.intersil.com/content/dam/Intersil/documents/tb34/tb347.pdf)** for details on reel specifications.

### Block Diagram



FIGURE 2. BLOCK DIAGRAM



## Pin Configuration



### Pin Descriptions





#### Absolute Maximum Ratings  $(T_A = +25^{\circ}C)$  Thermal Information

#### Voltages Applied to:



<span id="page-4-2"></span>

#### Recommended Operating Conditions



CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and *operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.*

#### NOTE:

<span id="page-4-0"></span>4.  $\theta_{JA}$  is measured with the component mounted on a high effective thermal conductivity test board in free air. See Tech Brief [TB379](http://www.intersil.com/content/dam/Intersil/documents/tb37/tb379.pdf) for details.

NOTE: Compliance to datasheet limits is assured by one or more methods: production test, characterization and/or design.

### <span id="page-4-1"></span>**Electrical Specifications**  $V_{DD} = 5V$ ,  $T_A = +25^\circ$ C, ENABLE = HI, WEN = HI, OSCEN = LO, SEL1 = HI, unless otherwise specified.



#### **Laser Amplifier**  $V_{DD} = 5V$ ,  $T_A = +25^\circ$ C, ENABLE = HI unless otherwise specified.







#### **Laser Amplifier**  $V_{DD} = 5V$ ,  $T_A = +25^{\circ}$ C, ENABLE = HI unless otherwise specified. (Continued)

NOTE:

<span id="page-5-0"></span>5. The amplifier linearity is calculated using a best fit method at three operating points. The output currents chosen are 20mA, 40mA, and 60mA. The transfer function for  $I_{\text{OUT}}$  is defined as follows:  $I_{\text{OUT}} = (I_{\text{IN}} \times \text{GAIN}) + I_{\text{OS}}$ .

#### <span id="page-5-2"></span>Laser Current Amplifier Outputs AC Performance  $v_{DD} = 5V$ ,  $I_{OUT} = 40 \text{mA DC with } 40 \text{mA pulse}$ ,  $T_A = +25 \text{°C unless}$ otherwise specified.



NOTE:

<span id="page-5-1"></span>6. Input timing is defined as WENx or ENABLE input pulse crosses 1.68V. Input pulse is standard 3.3V CMOS-level TTL input.





### APC Amplifier  $V_{DD} = 5V$ ,  $T_A = +25^\circ C$ ,  $R_{LOAD} = 2k\Omega$  to  $V_{REF}$  unless otherwise specified.

NOTE:

<span id="page-6-0"></span>7.  $\mathsf{R}_\mathsf{L}$  is total load resistance due to feedback resistor and load resistor. Recommended feedback resistor is 5kΩ.

#### **IOUT Control**



#### Oscillator Control





## <span id="page-7-2"></span>Timing Diagram



### <span id="page-7-1"></span>Typical Performance Curves









The ISL58831 oscillator frequency is controlled by the current being sourced at the R<sub>FREO</sub> pin. For a typical part, **Equation 1** (accurate to better than 5MHz at any frequency) should be used to determine the frequency of operation:

 $\mathsf{FREQ}_{(\mathsf{M} \mathsf{H} \mathsf{z})}$  = -5.9672  $\times$  10 $^{-10}$   $\times$   $\mathsf{R^{3}_{\mathsf{F} \mathsf{R} \mathsf{E} \mathsf{Q}}}$  $1.5839 \times 10^{-5} \times R_{\text{FREQ}}^2 - 0.1596 \times R_{\text{FREQ}} + 841.34$  $=$  -5.9672  $\times$  10<sup>-10</sup>  $\times$  R<sub>EREO</sub> +

<span id="page-7-0"></span>(EQ. 1)

Jan 28, 2016



### Applications Information

#### Enable and Read Operation

The ENABLE line powers up the chip and supplies bias to all the circuits. After being enabled, read current can be obtained by applying a current to the  $I_{INR}$  input. The read power is usually operated in an automatic power control loop, by varying the current in the I<sub>INR</sub> pin in response to the monitored laser light power. **Equation 2** is the defining equation for each amplifier:

$$
I_{OUT} = \frac{V_{DAC}}{R_{SET} + R_{INX}} \times GAM
$$
 (EQ. 2)

#### Oscillator Operation

Usually a laser will be noisy due to mode-hopping often caused by variable optical feedback into the laser.  ${\sf R}_{\sf F}$  current can be applied to reduce this noise effect by bringing the OSCEN pin high. The amplitude of the  $R_\mathsf{F}$  is set by the  $R_\mathsf{AMP}$  resistor and the frequency is set by the R<sub>FREQ</sub> resistor. See the "Typical Performance Curves" on page 8 for resistor set values.

 ${\sf R}_{\sf F}$  current is applied in a on/off fashion. Thus, if the  ${\sf R}_{\sf F}$ amplitude is 50mA<sub>P-P</sub>, 50mA will be added to the read current for half the R<sub>F</sub> cycle, and then 0mA will be added to the read current for half the  $R_F$  cycle. In this case, if the threshold current is only 40mA, the average laser power could exceed the intended read laser power by about 2mW, due to the 50% duty cycle current of 10mA above threshold. Therefore, in order to regulate the read power, it is necessary to make sure that the  $R_F$ amplitude is not much more than the required DC read current.

The circuit has a feature to increase the ability to turn off the laser for low threshold currents. At low read currents, the amplitude of the R<sub>F</sub> will be reduced as the amplitude of the read current is reduced.

#### Write Levels

Typical applications will have at least two write powers. The recommended method to control the write power level is to assign Channel 2 to the lowest power level above read and add in Channel 3 to obtain the highest write power level. This spreads the gain over the most amplifiers, allows the largest current level to the laser, reduces the sensitivity of each input and provides the most protection to the laser in case of erroneous input commands.

#### Write Switching Waveforms

The WEN lines are applied to a fast comparator set to 1.67V. This makes it possible to have predictable rise and fall propagation delays from the WEN write pulse inputs to the laser.

#### Power Supply Decoupling

Due to the high values of current being switched rapidly on and off, it is important to ensure that the power supply is well decoupled to ground. During switching, the  $V_{DD}$  undergoes severe current transients, thus every effort should be made to decouple the  $V_{DD}$  as close to the package as possible, and to route the laser cathode to the decoupling capacitor with a short wide trace. Symptoms that could arise include poor rise/fall times, current overshoot and poor settling response. Since even a well placed bypass capacitor will have a response limitation due to the lead inductance, it might be necessary to also place a lossy bead and a second decoupling capacitor on the supply side of the bead to prevent switching currents on the supply line from generating EMI.

#### Laser Diode Routing

<span id="page-8-1"></span>It is very important to minimize the inductance of the trace between the IOUT pin and the laser diode. This trace acts as an antenna for EMI, inhibits the flow of  ${\sf R}_{\sf F}$  and pulse current to the laser and absorbs  $\mathsf{R}_{\mathsf{F}}$  current into ground. The ground return from the laser cathode to the chip and decoupling capacitors is best as a wide plane on both sides of the trace leading to the laser anode.

Ringing of the waveform might be observed on the IOUT pin. The best way is to check the optical output of the laser with an optical probe. If ringing is confirmed that cannot be reduced by an improved layout, the addition of an RC snubber network right at the output of the laser driver may be helpful. Be aware however, that the rise time might be affected and that the pulse power might be affected by pattern dependent voltage build-up on the snubber capacitor. Users should expect to lose 0.5ns of tr/tf for every 1cm of distance from IOUT to the laser diode and back to the  $V_{DD}$  decoupling capacitor.

#### <span id="page-8-0"></span>Power Consumption Issues

The ISL58831 has been designed for low power consumption. When disabled, the part takes negligible power consumption, regardless of the state of the other pins. In addition, for  $V_{DD}$ <3.5V, the ISL58831 will shut down to less than 1mA of supply current.

When in normal operation, the ISL58831 total power consumption depends strongly on the laser diode current and voltage. Since the total power consumption under worst case conditions could approach one watt, the burden is on the user to dissipate the heat into the board ground plane or chassis. An in-depth discussion of the effects of ground plane layout and size can be found in application note **AN1091**.

An approximate equation for the device power consumption is shown in **Equation 3** (users must adjust accordingly for any duty cycle issues):

<span id="page-8-2"></span>
$$
P_{DISS} = ([I_S + (14 \times \Sigma I_{IN})) \times V_{CC}) + [I_{DIODE} \times (V_{CC} - V_{DIODE})]
$$
\n(EQ.3)

#### Where:

 $I_S = I_{S2}$  when oscillator off, or  $I_{S3}$  when oscillator on (see [page 5\)](#page-4-1)

 $\Sigma \bm{{\mathsf{I}}}_{\textsf{IN}}$  = Sum of all the  $\bm{{\mathsf{I}}}_{\textsf{IN}}$  currents

 $V_{DD}$  = Device power supply voltage

IDIODE = Laser diode current

 $V_{\text{DIODE}}$  = Forward voltage of laser diode at current of  $I_{\text{DIODE}}$ 

When using the ISL58831, the user must take extreme care not to exceed the maximum junction temperature of +150°C. Since the case-to-ambient thermal coefficient will dominate, and since this is very much defined by the user's thermal engineering, it is not practical to define a strict limit on power consumption.



Furthermore, the case-to-ambient thermal coefficient may not be known precisely.

To assist in worst case conditions, it is possible to monitor the silicon temperature of the ISL58831 by forcing current into the ENABLE pin, which will then be at a voltage of  $V_{DD} + V_{PN}$ , where  $V_{PN}$  is the forward biassed voltage of the ESD protection diode. Since ENABLE = HI is necessary for normal operation, the device can be operated as it would be in the real-life applications, while the temperature is monitored. The ISL58831 has been calibrated with a 1MΩ resistor to +10V connected in series with the ENABLE pin, which results in an input current of approximately 4.5µA. [Figure 7](#page-9-0) allows the silicon temperature to be determined directly. The graph shows the measured ENABLE pin to VDD pin differential voltage, which shows a linear voltage sensitivity of -2.26mV/°C. Users may wish to measure their specific part at +20°C (no warm-up) to allow for any statistical/process distribution, but the method is reliable and accurate.

By applying this method to the ISL58831 in an actual application, users can measure the silicon temperature under all operating conditions to determine whether their thermal engineering is sufficient. The thermal resistance of the QFN24 is +140°C/W when tested on a standard JEDEC JESD51-3 (single layer) test board. When using a standard JEDEC JESD51-7 (four layer) test board, the thermal resistance is +112°C/W. Actual thermal resistance is highly dependent on circuit board layout considerations.

#### Temperature Measurement Set-Up and **Results**

Example: Measure ENABLE - V<sub>DD</sub> under coolest condition of  $V_{DD}$  = 0V and  $V_{ENABLE}$  = 5V through 1MΩ. Suppose the result was 580mV at  $T_{AMBIENT}$  = +20 $^{\circ}$ C.

Now measure ENABLE -  $V_{DD}$  under the actual operating conditions. Suppose result (must be after thermal equilibrium has been reached) is 450mV, and the new  $I_{CC}$  value is 100mA.

Now one can calculate the temperature rise of (450 to 580)/  $-2.26 = +57$  °C. Using the power dissipation of  $PW = (V_{DD} * I_{CC}) \cdot (I_{CC} * V_{DD})$ , the  $\theta_{JA}$  of the application can be calculated.



<span id="page-9-0"></span>FIGURE 7. ISL58831 ON-CHIP THERMOMETER

**+5V**

**VDD**



### Revision History

The revision history provided is for informational purposes only and is believed to be accurate, but not warranted. Please go to the web to make sure that you have the latest revision.



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### <span id="page-11-0"></span>QFN (Quad Flat No-Lead) Package Family



**TOP VIEW**









#### **MDP0046**

#### **QFN (QUAD FLAT NO-LEAD) PACKAGE FAMILY (COMPLIANT TO JEDEC MO-220)**





NOTES:

- 1. Dimensioning and tolerancing per ASME Y14.5M-1994.
- 2. Tiebar view shown is a non-functional feature.
- 3. Bottom-side pin #1 I.D. is a diepad chamfer as shown.
- 4. N is the total number of terminals on the device.
- 5. NE is the number of terminals on the "E" side of the package (or Y-direction).
- 6. ND is the number of terminals on the "D" side of the package (or X-direction).  $ND = (N/2)-NE$ .
- 7. Inward end of terminal may be square or circular in shape with radius (b/2) as shown.
- 8. If two values are listed, multiple exposed pad options are available. Refer to device-specific datasheet.